

形式问题

1. 需要展示及介绍测试平台。
2. 对于自己假设的参数，如 V_{TH} ，需要提前说明。
3. 没有给出推算过程或逻辑，直接给出结果的一律无效。
4. 尽量使用工程单位 μm , nm , fF 等，而不是数学单位 $e-6$
5. 请将作业整理到一个PDF，题号回答清晰，建议全电子版书写；手写作业请确保字迹清晰，字迹模糊无法辨认的直接判错。
6. 作业迟交最高按60%分值计算，请确保按时提交作业。

Homework 1

2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_o 。

• $V_{GS}=0.8V$, 强反转区的 g_m 推导:

$$\begin{cases} L_{\min} = 0.35 \mu m \\ KP_n \approx 300 \mu A/V^2 \end{cases} \quad \longrightarrow \quad KP_n \approx 600 \mu A/V^2$$

$$I_D = \frac{1}{2} KP_n \frac{W}{L} (V_{GS} - V_{TH})^2$$

$$I_D = 200 \mu A, \Big|_{V_{TH}=0.46V} \quad g_m = 1.2 mA/V, \Big|_{V_{TH}=0.46V}$$

2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_o 。

• $V_{GS}=0.8V$, 强反转区的 r_o 推导:

$$r_o \approx \frac{1}{\lambda I_{DS}} = \frac{V_E \cdot L}{I_{DS}}$$

$$V_{En} = 4 \text{ V}/\mu\text{mL}$$

$$r_o \approx \frac{4 \cdot 0.18}{200\mu} = 3.6K\Omega$$

2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_0 。

• $V_{GS}=0.8V$, 强反转区的 g_m 和 r_0 检验:

	估算	仿真
I_d	200u	100u
g_m	1.2m	0.42m
r_0	3.6K	100K

×估算与仿真有较大差距

```
region = Saturati
id = 100.3509u
ibs = -1.6822e-20
ibd = -43.4021n
vgs = 800.0000m
vds = 1.8000
vbs = 0.0000
vth = 456.4051m
vdsat = 232.2942m
vod = 343.5949m
gm = 423.2997u
gds = 11.2628u
gmb = 98.3501u
cdtot = 988.0917a
cgtot = 1.9084f
cstot = 2.4746f
cbtot = 2.1628f
cgs = 1.3013f
cgd = 341.0737a
```

2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_o 。

- 估算参数矫正

```
* GENERAL PARAMETERS
*
+CALCACM = 1
+LMIN = 1.5E-7 LMAX = 1.0E-5
+LWMAX = 1.0E-4 TNOM = 25.0
+TOX = '3.87E-09+DTON_N18' TOXM = 3.87E-09
+NCH = 3.8694000E+17 LLN = 1.1205959
+WLN = 1.0599999 WWN = 0.8768474
+LL = 2.6352781E-16 LW = -2.2625584E-16
+WINT = -1.4450482E-09 WL = -2.3664573E-16
+WWL = -4.0000000E-21 MOBMOD = 1
+XL = '1.8E-8+DXL_N18' XW = '0.00+DXW_N18'

* MOBILITY PARAMETERS
*
+VSAT = 8.2500000E+04 PVSAT = -8.3000000E-10
+LUA = 7.7349790E-19 PUA = -1.0000000E-24
+UC = 1.2000000E-10 PUC = 1.5000000E-24
+PRWB = 0.2400000 PRWC = 0.4000000
+U0 = '(3.4000000E-02)*(1+0.05*Sigma)' LU0
+AO = 0.8300000 KETA = -3.0000000E-03
+A1 = 0.00 A2 = 0.9900000
+B0 = 6.0000000E-08 B1 = 0.00
*
```

✓ 栅极厚度预估正确

$\mu_p \approx 250 \text{ cm}^2/\text{Vs}$

$\mu_n \approx 600 \text{ cm}^2/\text{Vs}$

× 载流子流速高估近一倍

2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_0 。

- 参数矫正

	调整后估算	仿真
I_d	113u	100u
g_m	0.68m	0.42m
r_0	6.4K	89K

```
* ROUT PARAMETERS
*
+PCLM      = 1.2000000      PPCLM      = 2.9999999E-15
+PDIBLC2   = 3.8000000E-03  PPDIBLC2   = 2.7000001E-16
+DROUT     = 0.5600000      PSCBE1     = 3.4500000E+08
+PVAG      = 0.00          DELTA      = 1.0000000E-02
+ALPHA1    = 0.1764000     LALPHA1    = 7.6250000E-09
*
```

$$V_{En} = 4 \text{ V}/\mu\text{mL}$$

- V_{En} 在此工艺中调整为 $40V/\mu m$

2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_o 。

• $V_{GS}=0.5V$, 弱反转区的 g_m 推导:

$$I_{D,wi} = I_{D0} \frac{W}{L} e^{\frac{V_{GS}}{n k T / q}}$$

$$g_{m,wi} = \frac{I_{D,wi}}{n k T / q}$$

× n 作为一个跟反转程度有关的量, 随 V_{GS} 变化, 无法预估

× I_{D0} 未知

2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_o 。

• $V_{GS}=0.5V$, 弱反转区的 g_m 推导: (利用已有强反型区结果)

$$I_{DS} = K' \frac{W}{L} V_{GSTt}^2 \cdot \ln^2(1 + e^v), \quad v = \frac{V_{GST}}{V_{GSTt}} \quad V_{GSTt} = 2n \frac{kT}{q} \approx 70mV$$

已有 $I_D = 113\mu A, \Big|_{V_{GST}=0.34V}$



$$\ln^2(1 + e^v) \approx 5^2 = 25$$



$$v = 0.7, \Big|_{V_{GST}=0.04V}$$

$$I_D = 5.5\mu A, \Big|_{V_{GST}=0.04V}$$



$$\ln^2(1 + e^v) \approx 1.1^2 = 1.2$$

2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_o 。

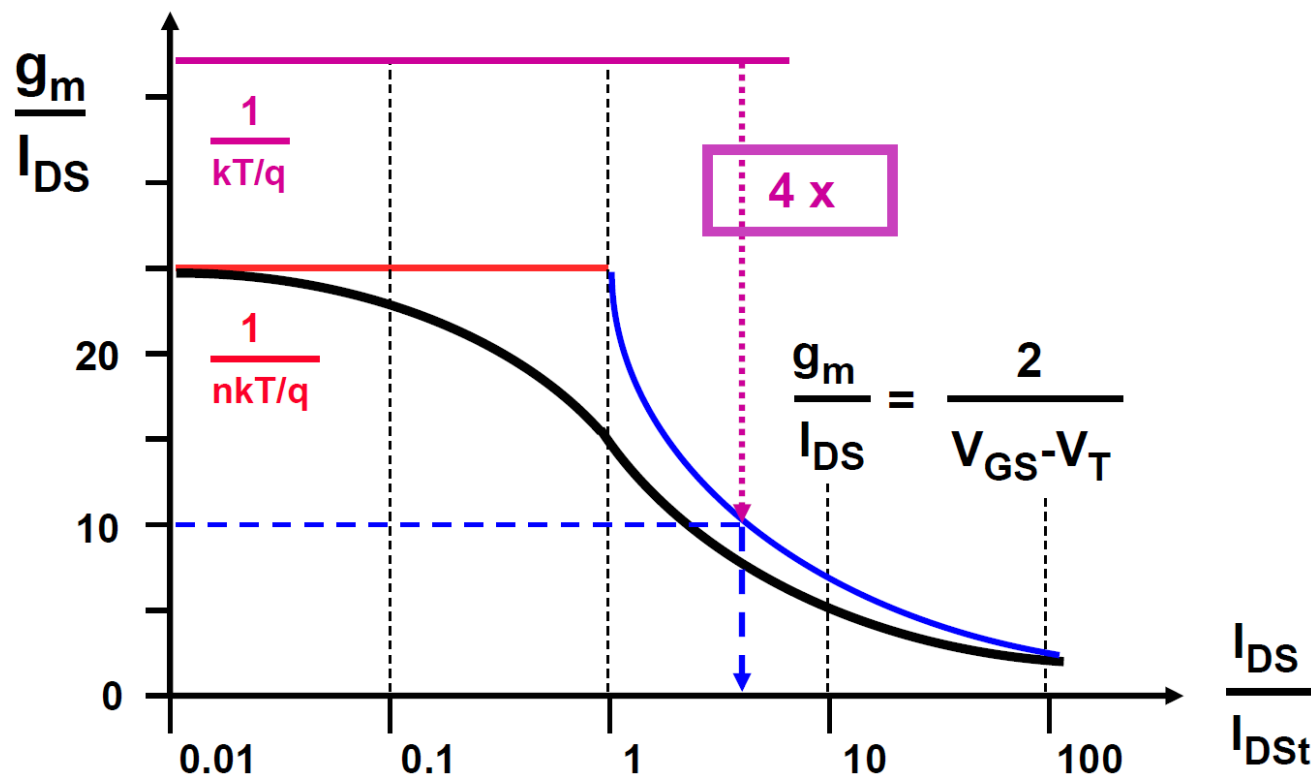
• $V_{GS}=0.5V$, 弱反转区的 g_m 推导:

$$I_D = 5.5\mu A, \Big|_{V_{GST}=0.04V}$$

$$\ln^2(1 + e^v) \approx 1.2$$

反型系数 i : $i = \frac{I_{DS}}{I_{DSt}} = \ln^2(1 + e^v)$

$$g_m = 82.5\mu/V, \Big|_{V_{TH}=0.46V}$$



2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_o 。

• $V_{GS}=0.5V$, 弱反转区的 r_o 推导:

$$r_o \approx \frac{1}{\lambda I_{DS}} = \frac{V_E \cdot L}{I_{DS}}$$

$$V_{en}=40V/\mu m$$

$$r_o \approx \frac{40 \cdot 0.18}{5.5\mu} = 1.3M\Omega$$

2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_0 。

• $V_{GS}=0.5V$, 弱反转区的 g_m 和 r_0 检验:

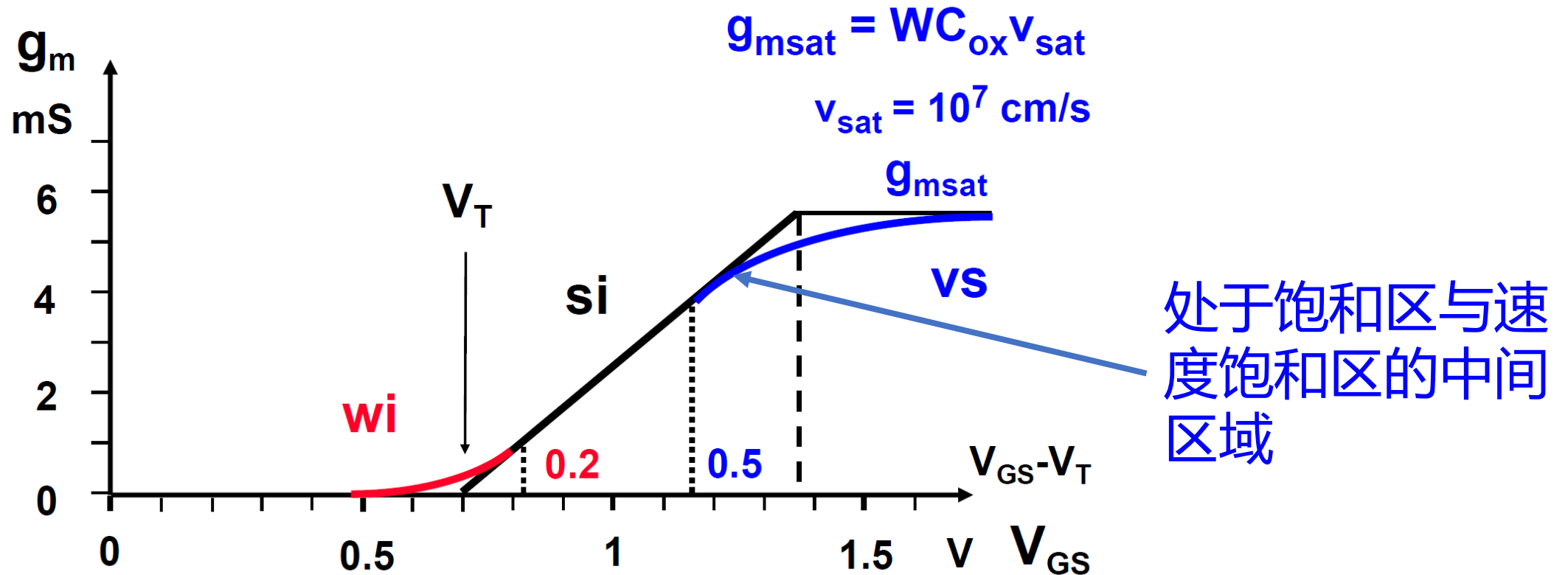
	估算	仿真
I_d	5.5μ	2μ
g_m	82.5μ	28μ
r_0	$1.3M$	$11M$

✓估算基本正确

```
[ NMO ]  
region = Saturati  
id = 2.0072u  
ibs = -3.3839e-22  
ibd = -902.0821p  
vgs = 500.0000m  
vds = 1.8000  
vbs = 0.0000  
vth = 404.6511m  
vdsat = 116.1837m  
vod = 95.3489m  
gm = 28.8373u  
gds = 85.4506n  
gmb = 8.4268u  
cdtot = 976.6265a  
cgtot = 6.8587f  
cstot = 7.1026f  
cbtot = 4.5589f  
cgs = 4.9752f  
cgd = 343.2256a
```

2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_o 。

• $V_{GS}=1.1V$, 速度饱和区的 g_m 推导:



2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_o 。

• $V_{GS}=1.1V$, 速度饱和区的 g_m 推导:

$$\frac{1}{g_m} = \frac{1}{g_{m,si}} + \frac{1}{g_{m,sat}}$$

$$g_{m,si} = 2KP_n \frac{W}{L} V_{GST} = 2.67m$$

$$g_{m,sat} = WC_{OX}v_{sat} = 1m$$

$$g_m = 0.73m$$

2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_0 。

• $V_{GS}=1.1V$, 速度饱和区的 r_0 推导:

$$\frac{g_{m,si}}{I_D} = \frac{2}{V_{GST}}$$

$$\frac{g_{m,sat}}{I_D} = \frac{1}{V_{GST}}$$



$$I_D \approx \frac{1}{1.8} \cdot g_m \cdot V_{GST} = 260\mu A$$

$$r_0 \approx \frac{1}{\lambda I_{DS}} = \frac{V_E \cdot L}{I_{DS}}$$

$$r_0 \approx \frac{40 \cdot 0.18}{0.26m} = 28K\Omega$$

$$V_{en}=40V/\mu m$$

2. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的 g_m 和 r_0 。

• $V_{GS}=1.1V$, 速度饱和区的 g_m 和 r_0 检验:

	估算	仿真
I_d	260u	240u
g_m	730u	500u
r_0	28K	62.5K

✓估算基本正确

```
[ NM0 ]  
region = Saturati  
id = 240.4028u  
ibs = -3.9974e-20  
ibd = -56.8244n  
vgs = 1.1000  
vds = 1.8000  
vbs = 0.0000  
vth = 456.5229m  
vdsat = 341.4154m  
vod = 643.4771m  
gm = 496.4637u  
gds = 16.0068u  
gmb = 116.4091u  
cdtot = 988.2450a  
cgtot = 1.9310f  
cstot = 2.4969f  
cbtot = 2.1538f  
cgs = 1.3361f  
cgd = 340.8963a  
ib = 3.9974e-20
```


3. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的特征频率 f_T , 并通过AC仿真得到所求的特征频率。

$$f_T = \frac{g_m}{2\pi C_{GS}}$$

$$C_{GS} \approx \frac{2}{3} WLC_{ox} \quad \approx 2W \text{ fF}/\mu m \text{ for } L_{min}$$

$$L_{min} C_{ox} \approx L_{min} \frac{\epsilon_{ox}}{t_{ox}} \approx 50 \epsilon_{ox} \approx 2 \text{ fF}/\mu m$$

$$f_T = \frac{g_m}{4\pi \cdot 1\mu \cdot \text{fF}/\mu m}$$

3. 估算 $V_{GS}=0.5V$, $0.8V$ 和 $1.1V$ 且 $V_{DS}=1.8V$ 时, $W/L=1\mu m/0.18\mu m$ 的NMOS的特征频率 f_T , 并通过AC仿真得到所求的特征频率。

$$f_T = \frac{g_m}{4\pi \cdot 1\mu \cdot fF/\mu m}$$

V_{GS}	仿真gm	算术fT	仿真fT
0.5V	28u	1.1G	12G
0.8V	420u	16.7G	36G
1.1V	500u	19.9G	41G

- 真实的 $C_{gs}=1.3fF$, 比我们预估的 $2fF$ 略小
- 弱反型区中的 C_{gs} 不能用 C_{ox} 类推

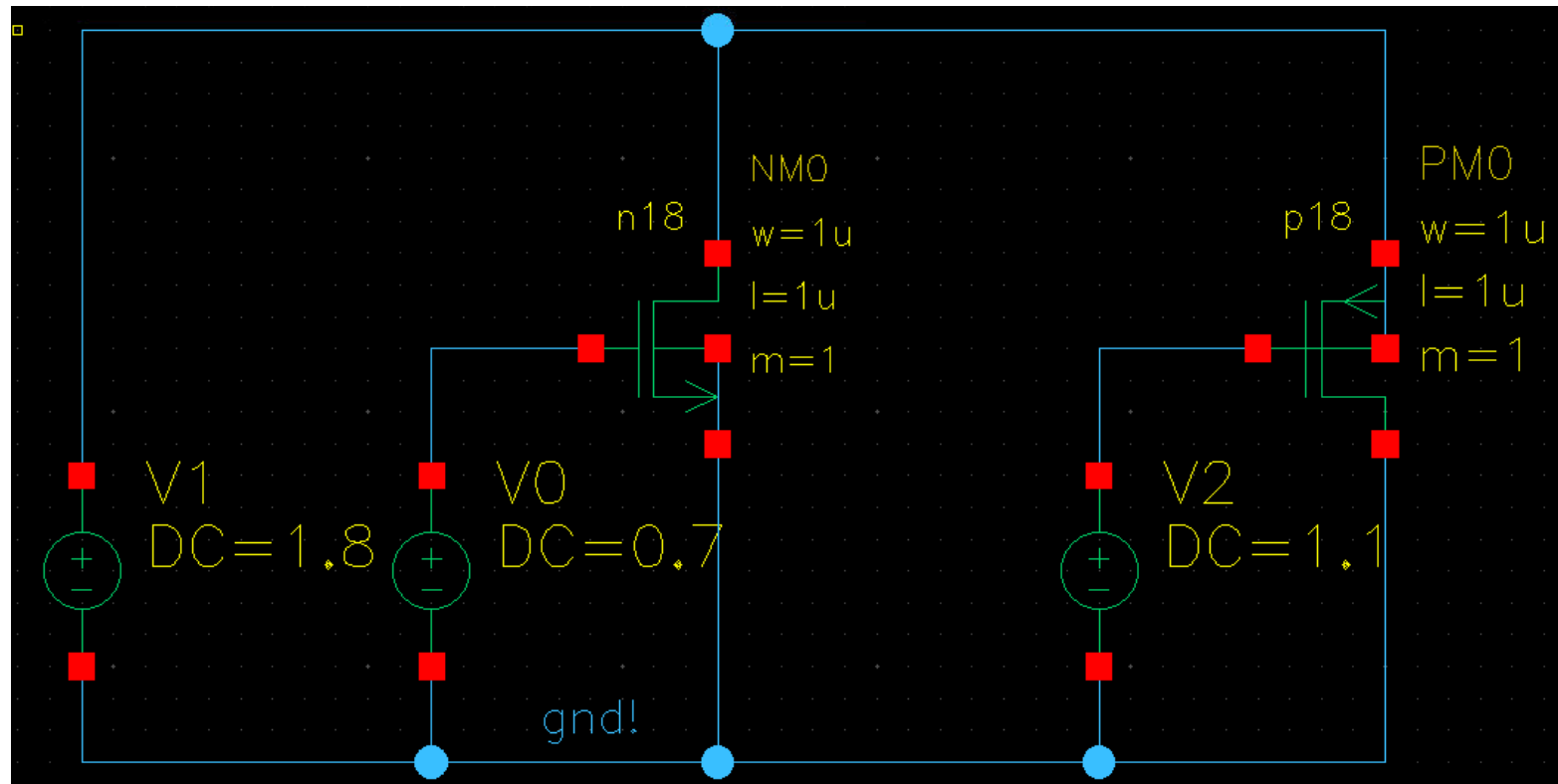
Homework 2

- 利用仿真结果，找到我们所使用工艺的 $\mu_{0p,n}$, C_{ox} , V_{THn} , V_{THp}

```

region = Saturati
id = 12.9769u
ibs = -2.1864e-21
ibd = -2.8580n
vgs = 700.0000m
vds = 1.8000
vbs = 0.0000
vth = 404.6616m
vdsat = 261.9176m
vod = 295.3384m
gm = 78.3552u
gds = 298.4982n
gmb = 22.6287u
cdtot = 976.9014a
cgtot = 7.3556f
cstot = 7.8072f
cbtot = 4.5240f
cgs = 5.6599f

```



```

region = Saturati
id = -2.4713u
ibs = 1.7020e-22
ibd = 11.4903p
vgs = -700.0000m
vds = -1.8000
vbs = 0.0000
vth = -422.6200m
vdsat = -250.9069m
vod = -277.3800m
gm = 16.0855u
gds = 61.2616n
gmb = 5.1132u
cdtot = 1.1470f
cgtot = 7.1159f
cstot = 8.3443f
cbtot = 4.1553f
cgs = 6.0843f

```

$$C_{oxn} = 8.55m \quad \leftarrow \quad C_{GS} \approx \frac{2}{3} W L C_{ox} \quad \rightarrow \quad C_{oxp} = 9.12m$$

$$u_{0n} = \frac{26u}{8.55m \cdot 0.09} = 33m \quad \leftarrow \quad I_D = \frac{1}{2} u_0 C_{GS} \frac{W}{L} (V_{GS} - V_{TH})^2 \quad \rightarrow \quad u_{0p} = \frac{4.94u}{9.12m \cdot 0.073} = 7.4m$$

- 利用仿真结果，找到我们所使用工艺的 $\mu_{0p,n}$, C_{ox} , V_{THn} , V_{THp}

NMOS

```
* GENERAL PARAMETERS
*
+CALCACM = 1
+LMIN = 1.5E-7
+WMAX = 1.0E-4
+T0X = '3.87E-09+DT0X N18'
+NCH = 3.8694000E+17
```

$$KP_n \approx 280 \mu A/V^2$$

```
* MOBILITY PARAMETERS
*
+VSAT = 8.2500000E+04      PVSAT = -8.
+LUA = 7.7349790E-19      PUA = -1.
+UC = 1.2000000E-10       PUC = 1.5
+PRWB = -0.2400000        PRWG = 0.4
+U0 = '(3.4000000E-02)*(1+0.05*Sigma)'
+A0 = 0.8300000           KETA = -3.
```

$$C_{oxn} = 8.55m$$

$$C_{GS} \approx \frac{2}{3} WLC_{ox}$$

$$\mu_{0n} = \frac{26\mu}{8.55m \cdot 0.09} = 33m$$

$$I_D = \frac{1}{2} \mu_0 C_{GS} \frac{W}{L} (V_{GS} - V_{TH})^2$$

PMOS

```
* GENERAL PARAMETERS
*
+CALCACM = 1
+LMIN = 1.5E-7
+WMAX = 1.0E-4
+T0X = '3.74E-09+DT0X P18'
+NCH = 5.5000000E+17
```

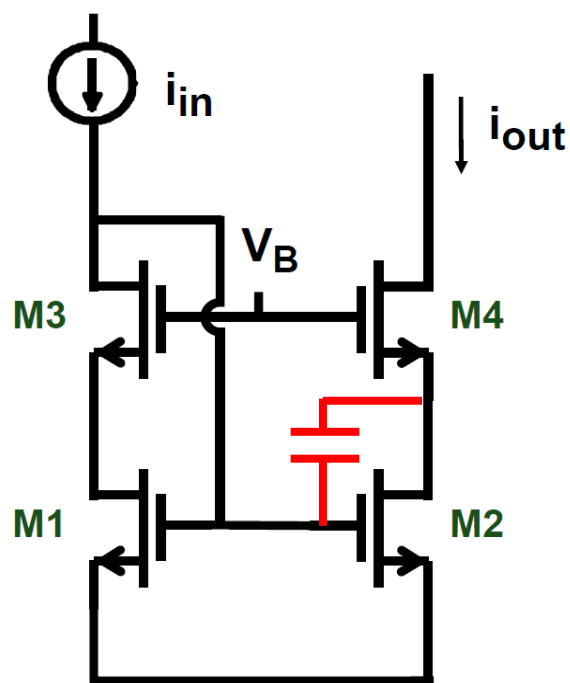
$$KP_p \approx 70 \mu A/V^2$$

```
* MOBILITY PARAMETERS
*
+VSAT = 1.0000000E+05      UA = 2
+PUA = -2.0000000E-24      UB = 1
+WUC = 3.1668000E-17       PUC = -
+PRWB = -0.4000000        PRWG = 6
+U0 = '(8.6610000E-03)*(1+0.05*Sigma)'
+A0 = 1.0000000           KETA = 2
```

$$C_{oxp} = 9.12m$$

$$\mu_{0p} = \frac{4.94\mu}{9.12m \cdot 0.073} = 7.4m$$

- 通过公式描述 V_B 的取值范围（提示：晶体管M1-M4均需要工作在饱和区）



$$\begin{cases} V_{DS1} > V_{GS1} - V_{TH1} \\ V_{DS3} > V_{GS3} - V_{TH3} \end{cases}$$

$$V_{GS3} + V_{GS1} - V_{TH1} < V_B < V_{GS1} + V_{TH3}$$

$$V_{GS3} - V_{TH1} < V_B - V_{GS1} < V_{TH3}$$

减小 V_{GS3} 以增加 V_B 的取值范围

改变 V_{GS1} 以改变 V_B 的电势偏移

令 $V_{GS3} = 0.4V, V_{GS1} = 0.6V$

得 $0.6 < V_B < 1$

-
- The schematic shows a differential pair of NMOS transistors, NM1 and NM2, with their sources connected to ground. The gates of NM1 and NM2 are connected to a common bias voltage V_B . The drain of NM1 is connected to a current source I_0 (DC = I_{bias}) and the drain of NM2 is connected to a load resistor R_L (DC = V_{DD}). The output voltage V_{out} is taken from the drain of NM2. The circuit is simulated with a DC source V_1 (DC = 0.5) and a DC source I_1 (DC = V_{DD}). The output voltage V_0 is measured across the load resistor R_L .

Sweep Range

Start Stop

☐ Linear

☒ Dec Points Per Dec

☐ Oct

☐ List

☐ Monte Carlo ☒ More Options

Sweep Variable

☐ Temperature

☒ Parameter Name

☐ Source

Sweep Range

Start Stop

☒ Linear ☒ Step Size ☐ Number Of Points

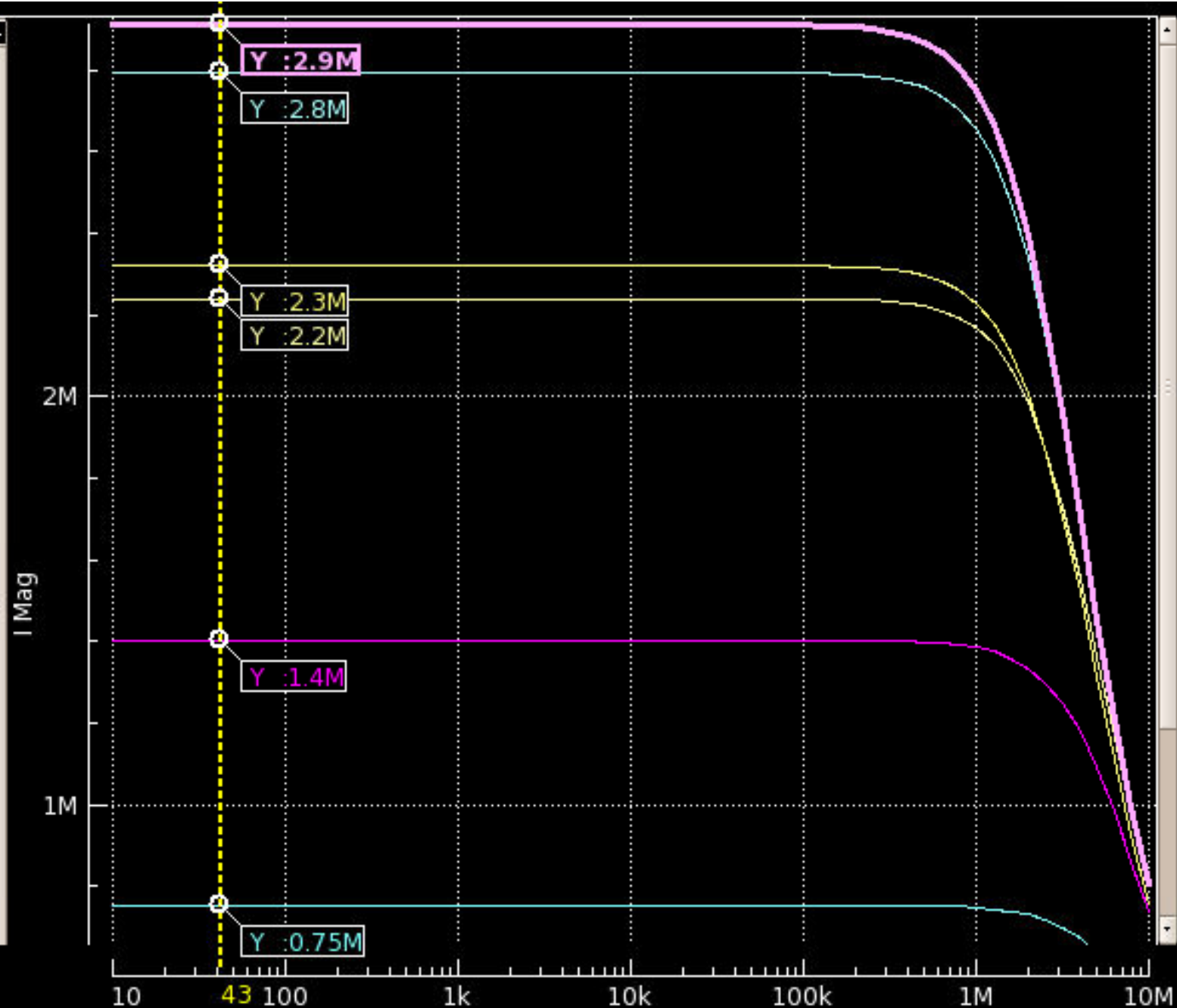
☐ Dec

☐ Oct

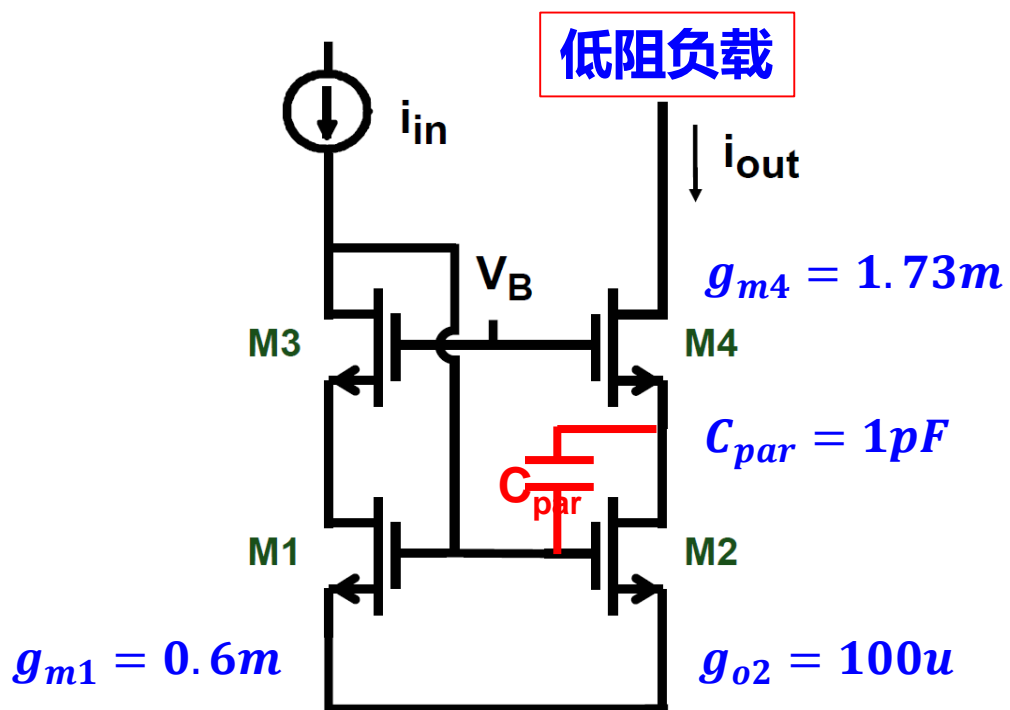
☐ List

☐ AC Statement

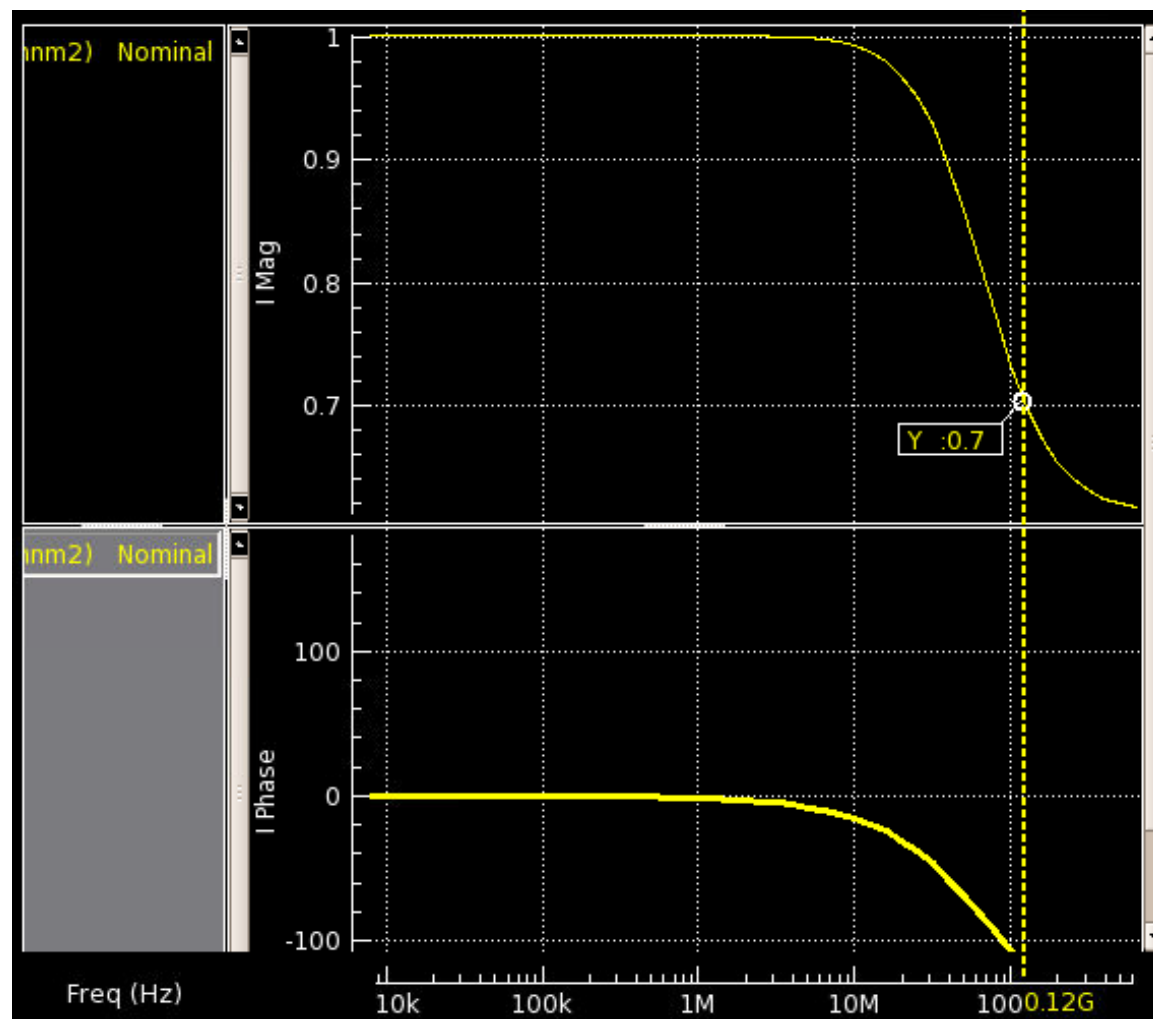
rout-vb=0.4	Nominal
rout-vb=0.5	Nominal
rout-vb=0.6	Nominal
rout-vb=0.7	Nominal
rout-vb=0.8	Nominal
rout-vb=0.9	Nominal
rout-vb=1	Nominal
rout-vb=1.1	Nominal
rout-vb=1.2	Nominal
rout-vb=1.3	Nominal
rout-vb=1.4	Nominal



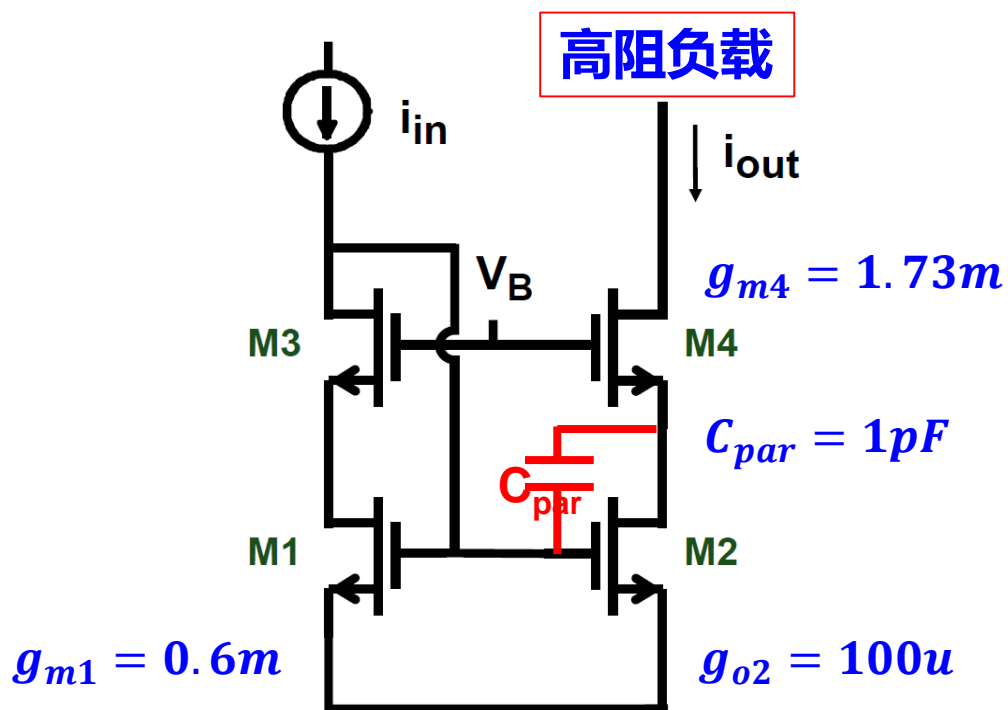
- 在Cascode电流镜中，假设有寄生电容 C_{par} ，利用公式估算并用仿真验证该电流镜的频率特性。（可以自由设置偏置、晶体管的尺寸以及寄生电容）



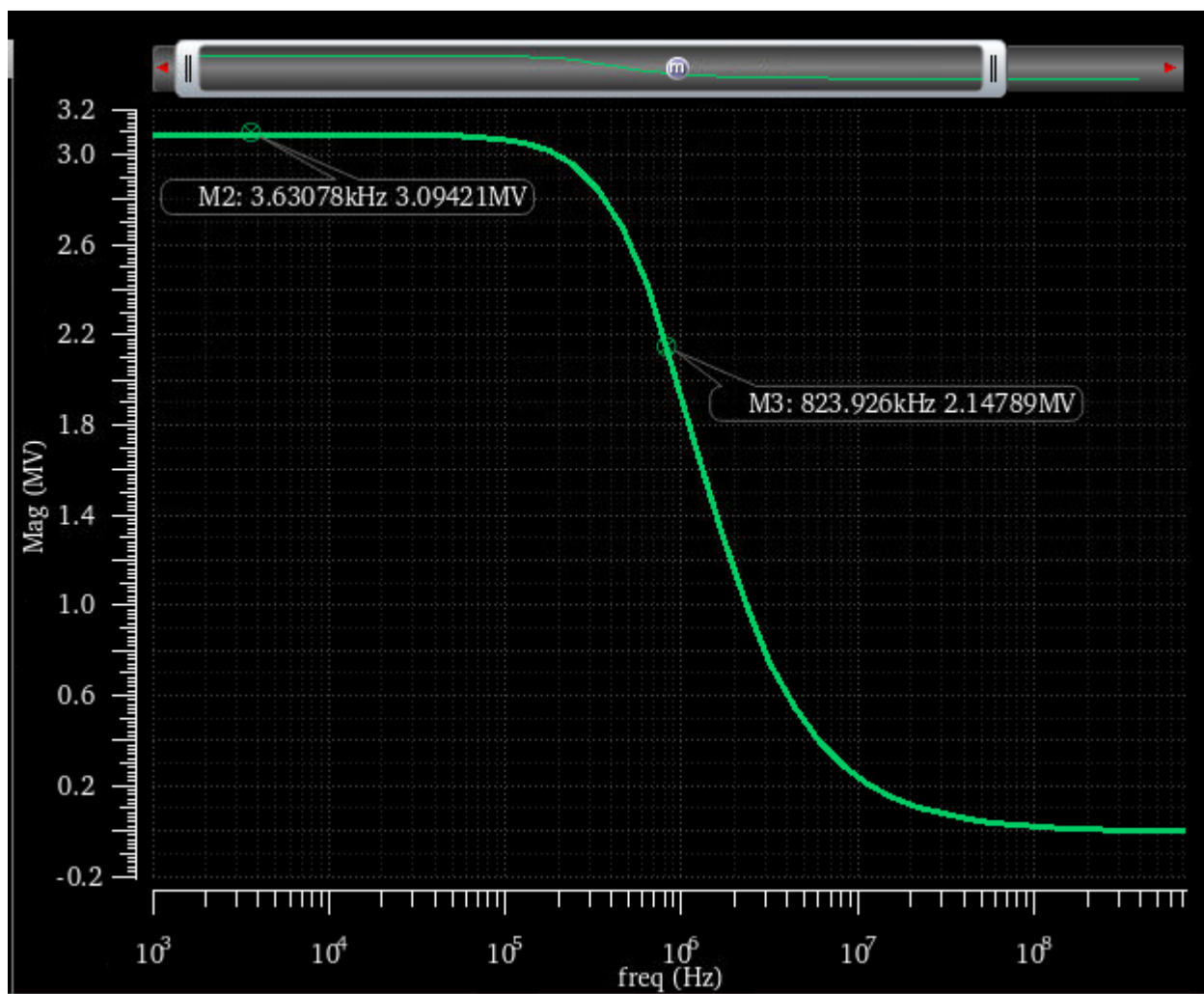
$$f_c = \frac{g_{m4}}{2\pi \cdot (1 + B) \cdot C_{par}} = 0.14GHz$$



- 在Cascode电流镜中，假设有寄生电容 C_{par} ，利用公式估算并用仿真验证该电流镜的频率特性。（可以自由设置偏置、晶体管的尺寸以及寄生电容）



$$f_c = \frac{g_{o2}}{2\pi \cdot (1 + B) \cdot C_{par}} = 796kHz$$



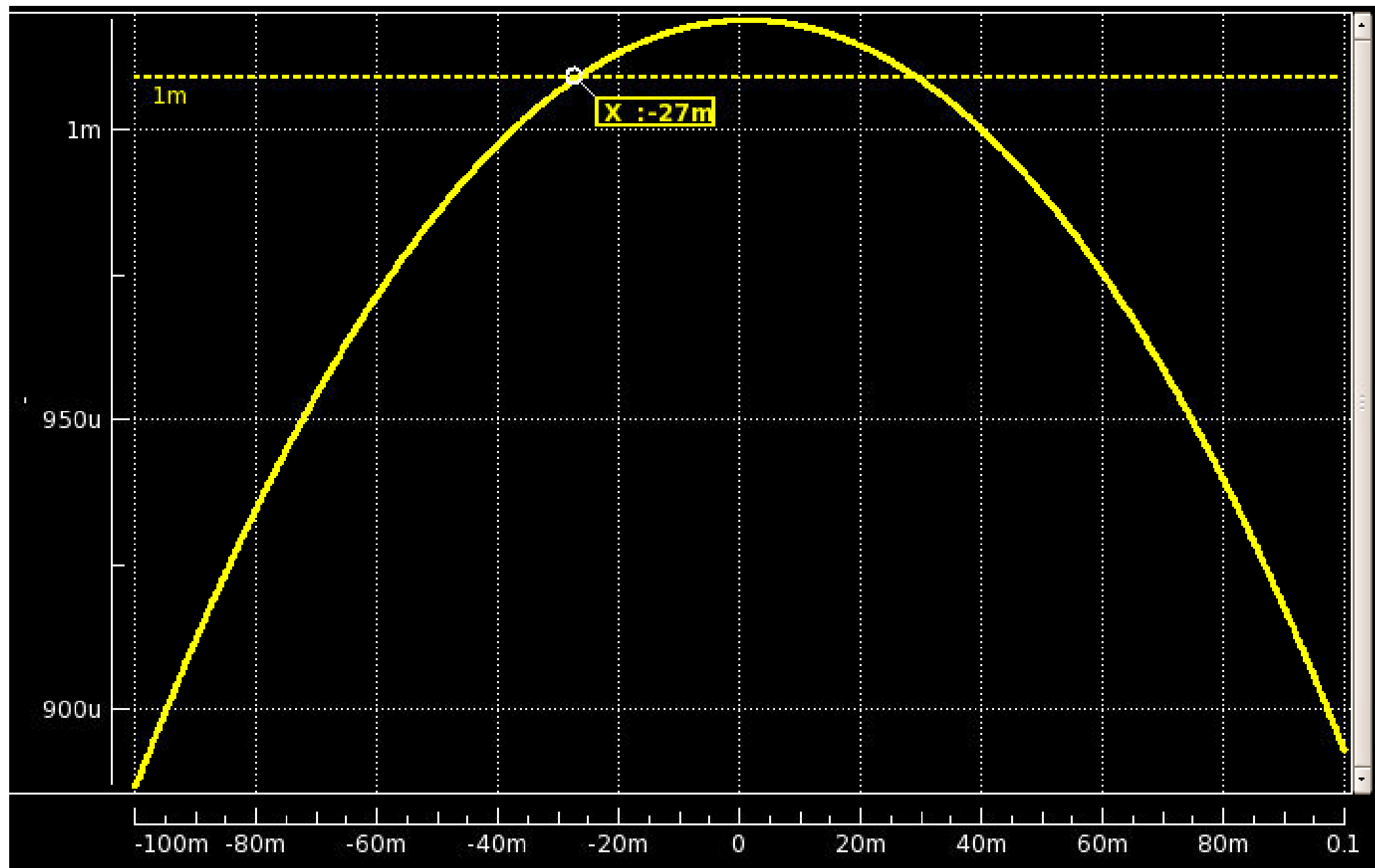
- 假设差分对偏置电流为200uA, $W/L=20\mu\text{m}/1\mu\text{m}$, 根据理论分析和仿真验证。

1. 计算 $g_m > 99\% \cdot g_{m,\text{max}}$ 的区间。
2. 计算差分输出电流为198uA时的差分输入电压。
3. 如果需要把问题2中求得的电压扩大一倍, 差分对的W需要如何修改?

$$\frac{i_{\text{Od}}}{I_B} = \frac{v_{\text{Id}}}{(V_{\text{GS}} - V_{\text{T}})} \sqrt{1 - \frac{1}{4} \left(\frac{v_{\text{Id}}}{V_{\text{GS}} - V_{\text{T}}} \right)^2}$$

$$\sqrt{1 - \frac{1}{4} \left(\frac{V_{\text{ID}}}{V_{\text{GST}}} \right)^2} = 99\%$$

$$V_{\text{ID}} = 0.28 \cdot V_{\text{GST}} \quad \rightarrow \quad V_{\text{ID}} = 53\text{mV}$$



- 假设差分对偏置电流为200uA, $W/L=20\mu\text{m}/1\mu\text{m}$, 根据理论分析和仿真验证。

1. 计算 $g_m > 99\% \cdot g_{m,\text{max}}$ 的区间。
2. 计算差分输出电流为198uA时的差分输入电压。
3. 如果需要把问题2中求得的电压扩大一倍, 差分对的W需要如何修改?

$$\frac{i_{\text{Od}}}{I_B} = \frac{V_{\text{Id}}}{(V_{\text{GS}} - V_{\text{T}})} \sqrt{1 - \frac{1}{4} \left(\frac{V_{\text{Id}}}{V_{\text{GS}} - V_{\text{T}}} \right)^2}$$

$$V_{\text{ID}} = \sqrt{2} \cdot V_{\text{GST}} \quad \Rightarrow \quad V_{\text{ID}} = 380\text{m}$$

V_{GST} 扩大一倍 =》晶体管宽长减小到原来的1/4

